

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/825,816	<b>Applicant(s)/Patent under Reexamination</b> KIM ET AL.
	<b>Examiner</b> Chuc D. Tran	<b>Art Unit</b> 2821

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner